

July 1988 Revised September 2000

74ACT823 9-Bit D-Type Flip-Flop

General Description

The ACT823 is a 9-bit buffered register. It features Clock Enable and Clear which are ideal for parity bus interfacing in high performance microprogramming systems. The ACT823 offers noninverting outputs.

Features

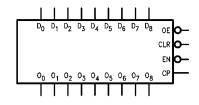
- Outputs source/sink 24 mA
- 3-STATE outputs for bus interfacing
- Inputs and outputs are on opposite sides
- TTL compatible inputs

Ordering Code:

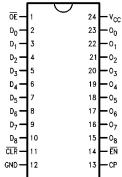
l	Order Number	Package Number	Package Description
	74ACT823SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
	74ACT823MTC	MTC24	24-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
	74ACT823SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code. (SPC not available in Tape and Reel.)

Logic Symbols



Connection Diagram



Pin Descriptions

Pin Names	Description
D ₀ -D ₈	Data Inputs
D ₀ -D ₈ O ₀ -O ₈ OE	Data Outputs
ŌĒ	Output Enable
CLR	Clear
CP	Clock Input
EN	Clock Enable

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Functional Description

The ACT823 consists of nine D-type edge-triggered flipflops. These have 3-STATE outputs for bus systems organized with inputs and outputs on opposite sides. The buffered clock (CP) and buffered Output Enable (OE) are common to all flip-flops. The flip-flops will store the state of their individual D-type inputs that meet the setup and hold time requirements on the LOW-to-HIGH CP transition. With OE LOW, the contents of the flip-flops are available at the outputs. When $\overline{\text{OE}}$ is HIGH, the <u>out</u>puts go to the high impedance state. Operation of the OE input does not affect the state of the flip-flops. In addition to the Clock and Output Enable pins, there are Clear (CLR) and Clock Enable (EN) pins. These devices are ideal for parity bus interfacing in high performance systems.

When $\overline{\text{CLR}}$ is LOW and $\overline{\text{OE}}$ is LOW, the outputs are LOW. When <u>CLR</u> is HIGH, data can be entered into the flip-flops. When $\overline{\mathsf{EN}}$ is LOW, data on the inputs is transferred to the outputs on the LOW-to-HIGH clock transition. When the EN is HIGH, the outputs do not change state, regardless of the data or clock input transitions.

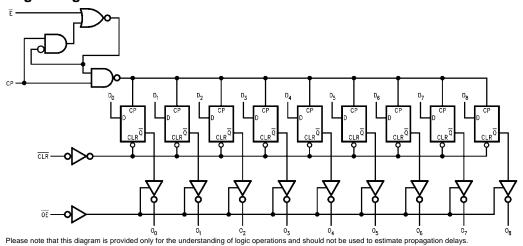
Function Table

		Inputs			Internal	Output	Fatia
ŌE	CLR	EN	СР	D	Q	0	Function
Н	Χ	L		L	L	Z	High Z
Н	Χ	L	~	Н	Н	Z	High Z
Н	L	Χ	Χ	Χ	L	Z	Clear
L	L	X	Χ	X	L	L	Clear
Н	Н	Н	Χ	Χ	NC	Z	Hold
L	Н	Н	Χ	X	NC	NC	Hold
Н	Н	L	~	L	L	Z	Load
Н	Н	L	~	Н	Н	Z	Load
L	Н	L	~	L	L	L	Load
L	Н	L	~	Н	Н	Н	Load

- H = HIGH Voltage Level
- L = LOW Voltage Level
- X = Immaterial
- Z = High Impedance

 ✓ = LOW-to-HIGH Transition
 NC = No Change

Logic Diagram



125 mV/ns

Absolute Maximum Ratings(Note 1)

070V C

Supply Voltage (V $_{CC}$) -0.5 V to 7.0 V

DC Input Diode Current (I_{IK}) $V_{I} = -0.5V$

−20 mA +20 mA

 $\label{eq:V_l} \begin{aligned} V_l &= V_{CC} + 0.5 \text{V} \\ \text{DC Input Voltage (V_l)} \end{aligned}$

DC Output Diode Current (I_{OK})

 $V_{O} = -0.5V$ -20 mA $V_{O} = V_{CC} + 0.5V$ +20 mA

DC Output Voltage (V_O) -0.5V to $V_{CC} + 0.5V$

DC Output Source or Sink Current

 (I_O) ±50 mA

DC V_{CC} or Ground Current

per Output Pin (I_{CC} or I_{GND}) $\pm 50 \text{ mA}$

Storage Temperature (T_{STG}) $-65^{\circ}C$ to $+150^{\circ}C$

Junction Temperature (T_J)

PDIP 140°C

Recommended Operating Conditions

Minimum Input Edge Rate (ΔV/Δt)

 V_{IN} from 0.8V to 2.0V V_{CC} @ 4.5V, 5.5V

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. Fairchild does not recommend operation of FACT™ circuits outside databook specifications.

DC Electrical Characteristics

Symbol	Parameter	v _{cc}	T _A = 25°C		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	Units	Conditions	
Symbol		(V)	Тур	p Guaranteed Limits		Uillis		
V _{IH}	Minimum HIGH Level	4.5	1.5	2.0	2.0	V	V _{OUT} = 0.1V	
	Input Voltage	5.5	1.5	2.0	2.0	V	or V _{CC} -0.1V	
V _{IL}	Maximum LOW Level	4.5	1.5	0.8	0.8	V	$V_{OUT} = 0.1V$	
	Input Voltage	4.5	1.5	0.8	0.8	v	or V _{CC} -0.1V	
V _{OH}	Minimum HIGH Level	4.5	4.49	4.4	4.4	V	I _{OLIT} = -50 μA	
			5.49	5.4	5.4	V	1 _{OUT} = -30 μA	
							$V_{IN} = V_{IL}$ or V_{IH}	
		4.5		3.86	3.76	V	$I_{OH} = -24 \text{ mA}$	
				4.86	4.76		$I_{OH} = -24 \text{ mA (Note 2)}$	
V _{OL}	Maximum LOW Level	4.5	0.001	0.1	0.1	V	Ι _{ΟΙΙΤ} = 50 μΑ	
	Output Voltage	5.5	0.001	0.1	0.1	v	1007 = 30 μΑ	
							$V_{IN} = V_{IL}$ or V_{IH}	
		4.5		0.36	0.44	V	$I_{OL} = 24 \text{ mA}$	
		5.5		0.36	0.44		I _{OL} = 24 mA (Note 2)	
I _{IN}	Maximum Input	5.5		±0.1	±1.0	μА	$V_I = V_{CC}$, GND	
	Leakage Current	3.3		10.1	±1.0	μΛ	VI = VCC, GIVD	
I _{OZ}	Maximum 3-STATE	5.5		±0.5	±5.0	μА	$V_I = V_{IL}, V_{IH}$	
	Current	5.5		±0.5	±3.0	μА	$V_O = V_{CC}$, GND	
I _{CCT}	Maximum I _{CC} /Input	5.5	0.6		1.5	mA	$V_I = V_{CC} - 2.1V$	
I _{OLD}	Minimum Dynamic	5.5			75	mA	V _{OLD} = 1.65V Max	
I _{OHD}	Output Current (Note 3)	5.5			-75	mA	V _{OHD} = 3.85V Min	
Icc	Maximum Quiescent Supply Current	5.5		8.0	80	μА	V _{IN} = V _{CC} or GND	

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

AC Electrical Characteristics

	Parameter	V _{cc}		T _A = +25°C		T _A = -40°	C to +85°C	
Symbol		(V)	(V) C _L = 50pF			$C_L = 50 pF$		Units
		(Note 4)	Min	Тур	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	5.0	120	158		109		MHz
t _{PLH}	Propagation Delay CP to O _n	5.0	1.5	5.5	9.5	1.5	10.5	ns
t _{PHL}	Propagation Delay CP to O _n	5.0	2.0	5.5	9.5	1.5	10.5	ns
t _{PHL}	Propagation Delay CLR to On	5.0	2.5	8.0	13.5	2.0	15.5	ns
t _{PZH}	Output Enable Time OE to On	5.0	1.5	6.0	10.5	1.5	11.5	ns
t _{PZL}	Output Enable Time OE to On	5.0	2.0	6.5	11.0	1.5	12.0	ns
t _{PHZ}	Output Disable Time OE to On	5.0	1.5	6.5	11.0	1.5	12.0	ns
t _{PLZ}	Output Disable Time OE to On	5.0	1.5	6.0	10.5	1.5	11.5	ns

Note 4: Voltage Range 5.0 is 5.0V ± 0.5V

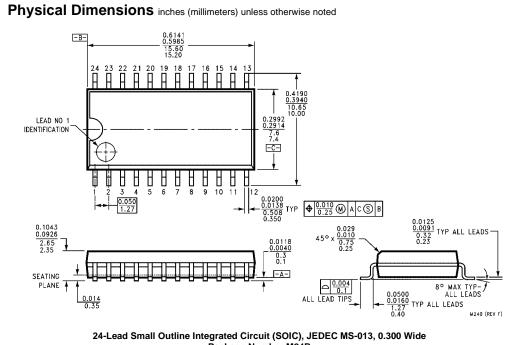
AC Operating Requirements

Symbol	Parameter	V _{CC} (V)	T _A = +25°C, C ₁ = 50 pF		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $C_1 = 50 \text{ pF}$	Units
		(Note 5)	= -		anteed Minimum	
t _S	Setup Time, HIGH or LOW D to CP	5.0	0.5	2.5	2.5	ns
t _H	Hold Time, HIGH or LOW D _n to CP	5.0	0	2.5	2.5	ns
t _S	Setup Time, HIGH or LOW EN to CP	5.0	0	2.0	2.5	ns
t _H	Hold Time, HIGH or LOW EN to CP	5.0	0	1.0	1.0	ns
t _W	CP Pulse Width HIGH or LOW	5.0	2.5	4.5	5.5	ns
t _W	CLR Pulse Width, LOW	5.0	3.0	5.5	5.5	ns
t _{REC}	CLR to CP Recovery Time	5.0	1.5	3.5	4.0	ns

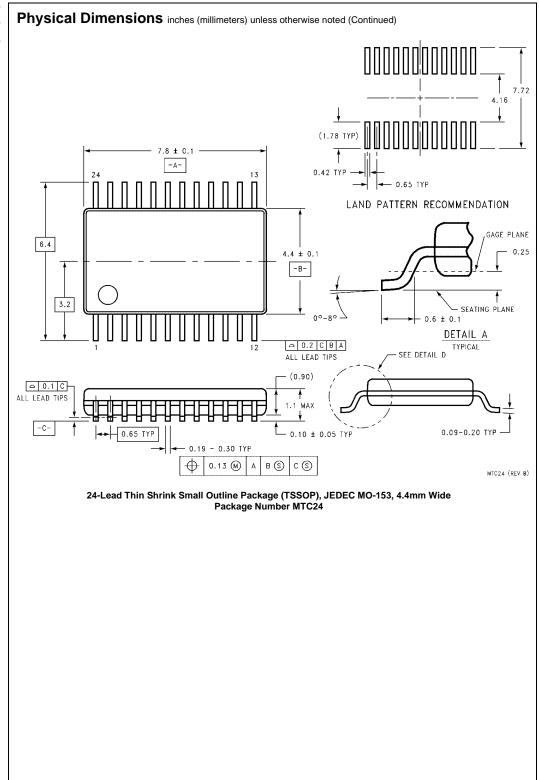
Note 5: Voltage Range 5.0 is 5.0V ± 0.5V

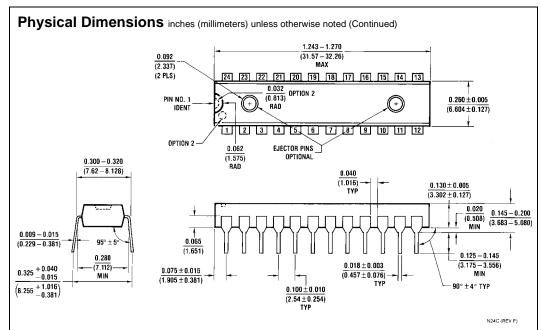
Capacitance

Symbol	Parameter	Тур	Units	Conditions	
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = OPEN	
C _{PD}	Power Dissipation Capacitance	44	pF	$V_{CC} = 5.0V$	



24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide Package Number M24B





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N24C

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